



Specification for Approval

Date: 2019/10/16





深圳臺慶 Customer:

	TAI-TECH P/N:	HCB3216KV-121T5	50				
	CUSTOMER P/N:						
	DESCRIPTION:						
	QUANTITY:	pcs	<u>. </u>				
REN	MARK:						
	Cu	stomer Approval Feedba	ıck				

西北臺慶科技股份有限公司 TAI-TECH Advanced Electronics Co., Ltd

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High Current Ferrite Chip Bead(Lead Free)

HCB3216KV-121T50

		ECN HISTOR	RY LIST	Γ	
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	14/01/24	變更電鍍錫層厚度 3.0um min.=>3.5um min.	楊祥忠	羅培君	張嘉玲
2.0	14/08/01	變更 Reflow 圖示	楊祥忠	羅培君	張嘉玲
2.1	14/08/01	修正包裝帶尺寸	楊祥忠	羅培君	張嘉玲
3.0	16/01/26	修訂下列可靠度溫度同 Operating Temperature 1.High Temperature Exposure(Storage) 2.High Temperature Operational Life 3.Thermal shock 4.Temperature Cycling	楊祥忠	詹偉特	張嘉玲
4.0	17/02/16	修訂 Recommended PC Board Pattern	楊祥忠	詹偉特	張嘉玲
備					
註					

TAI-TECH KBM01-191000353 P2.

High Current Ferrite Chip Bead(Lead Free)

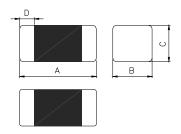
HCB3216KV-121T50

Certificate

1.Features

- 1. Monolithic inorganic material construction.
- 2. Closed magnetic circuit avoids crosstalk.
- 3. Suitable for reflow soldering.
- 4. Shapes and dimensions follow E.I.A. spec.
- 5. Available in various sizes.
- 6. Excellent solder ability and heat resistance.
- 7. High reliability. Reliability test meet AEC-Q200.
- 8. 100% Lead(Pb) & Halogen-Free and RoHS compliant.
- 9. Low DC resistance structure of electrode to prevent wasteful electric power consumption.
- 10. Operating Temperature: -55~+150°C (Including self-temperature rise)

2.Dimensions



Chip Size			
Α	3.20±0.20		
В	1.60±0.20		
С	1.10±0.20		
D	0.50±0.30		

Units: mm

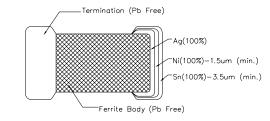
3.Part Numbering



D: Category Code E: Impedance

121=120 Ω T=Taping and Reel, B=Bulk(Bags) F: Packaging

G: Rated Current 50=5000mA

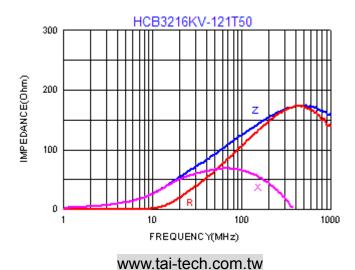


4. Specification

Tai-Tech Part Number	Impedance (Ω)	Test Frequency (Hz)	DC Resistance (Ω) max.	Rated Current (mA) max.
HCB3216KV-121T50	120±25%	60mV/100M	0.02	5000

- Rated current: based on temperature rise test
- In compliance with EIA 595

Impedance-Frequency Characteristics



TAI-TECH KBM01-191000353 P3.

5. Reliability and Test Condition

Item		Performance		Test Condition
Series No.	FCB	FCM	HCB	
Operating Temperature	(-55~+150℃ Including self-temperature r	ise)	-
Transportation Storage Temperature		For long storage conditions, please see the Application Notice		
Impedance (Z)				Agilent4291 Agilent E4991 Agilent4287
DC Resistance	Refer to standard electric	cal characteristics list		Agilent16192 Agilent 4338
Rated Current				DC Power Supply Over Rated Current requirements, there will be some risk
Temperature Rise Test	Rated Current < 1A ∆T 20 Rated Current ≧ 1A ∆T 4			Applied the allowed DC current. Temperature measured by digital surface Thermometer.
High Temperature Exposure(Storage)				Preconditioning:Run through IR reflow for 2 times. (IPC/JEDEC J-STD-020D Classification Reflow Profiles Temperature: 150±2°C Duration: 1000hrs Min. Measured at room temperature after placing for 24±2 hrs
Temperature Cycling	Appearance: No damag Impedance: within±15% Inductance: within±10% Q: Shall not exceed the RDC: Within ±15% of ir	of initial value of initial value	Preconditioning:Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles Condition for 1 cycle Step1: -55±2°C 30min Min Step2: 150±2°C transition time 1min MAX. Step3: 150±2°C 30min Min. Step4: Low temp. transition time 1min MAX. Number of cycles: 1000 Measured at room temperature after placing for 24±2 hrs	
Biased Humidity (AEC-Q200)	Appearance : No damage. Impedance : within±15% of initial value			Preconditioning:Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles Humidity:85±3%RH. Temperature:85±2°C. Duration:1000 hrs Min. Measured at room temperature after placing for 24±2 hrs
High Temperature Operational Life	Inductance: within±10% Q: Shall not exceed the RDC: Within ±15% of ir		Preconditioning:Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles Temperature : 150±2°C Duration : 1000hrs Min. with 100% rated current. Measured at room temperature after placing for 24±2 hrs	
External Visual	Appearance : No damag	ge.		Inspect device construction, marking and workmanship. Electrical Test not required.
Physical Dimension	According to the product	specification size measuren	nent	According to the product specification size measurement
Resistance to Solvents	Appearance : No damage	Э.		Add aqueous wash chemical - OKEM clean or equivalent.

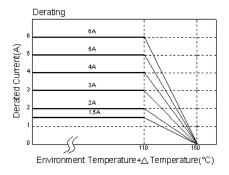
 TAI-TECH
 KBM01-191000353
 P4.

Item	Performance	Test Condition				
		Preconditioning:Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles Test condition:				
Mechanical Shock		Туре	Peak alue (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vi)ft/sec
		SMD Lead	100	6	Half-sine Half-sine	12.3 12.3
		3 shoo	ks in	each	direction	
Vibration	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: Within ±15% of initial value and shall not exceed the specification value		Preconditioning:Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles Oscillation Frequency: 10Hz ~ 2KHz ~ 10Hz for 20 minute Equipment: Vibration checker Total Amplitude:5g Testing Time: 12 hours(20 minutes, 12 cycles each of 3 orientations) °			
				Condition K cycles: 3	()	
Resistance to Soldering			ature C)	Time (s)	Temperati ramp/imm and emers	ersion
Heat			emp)	30 ±5	1℃/s-4℃ abo 183℃,90	ve
Thermal shock	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: Within ±15% of initial value and shall not exceed the specification value	Preconditioning:Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles Condition for 1 cycle Step1: -55±2°C 15±1min Step2: 150±2°C within 20 Sec. Step3: 150±2°C 15±1min Number of cycles: 300 Measured at room temperature after placing for 24±2hrs				ssification
ESD	Appearance: No damage.	10%	t _r	Time	(ns)	
Solder ability	More than 95% of the terminal electrode should be covered with solder.	a.MethodB,4hrs@155°Cdryheat @235°C±5°C b. Method B @ 215°C±5°C category 3.(8hours ± 15 min) c. Method D category 3. (8hours ± 15 min)@ 260°C±°C Preheat: 150°C,60sec. Solder: Sn96.5%-Ag3%-Cu0.5% Solder temperature: 245±5°C Flux for lead free: Rosin. 9.5% Dip time: 4±1sec. Depth: completely cover the termination.				
Electrical Characterization	Refer Specification for Approval	Summary to show Min, Max, Mean and Standard deviation				
Flammability	Electrical Test not required.	V-0 or \	V-1 are	accepta	ble.	

TAI-TECH KBM01-191000353 P5.

Item	Performance	Test Condition
Board Flex	Appearance : No damage.	Preconditioning:Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles Place the 100mm X 40mm board into a fixture similar to the one shown in below Figure with the component facing down. The apparatus shall consist of mechanical means to apply a force which will bend the board (D) x = 2 mm minimum. The duration of the applied forces shall be 60 (+ 5) sec. The force is to be applied only once to the board.
Terminal strength	Appearance : No damage.	Preconditioning:Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020D Classification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a 17.7 N (1.8 Kg) force to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to thecomponent being tested.

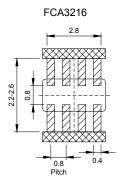
**Derating Curve



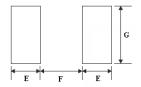
6. Soldering and Mounting

6-1. Recommended PC Board Pattern

	Chip Size						Pattern ow Sold	
Series	Туре	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)	F(mm)	G(mm)
	1005	1.0±0.10	0.50±0.10	0.50±0.10	0.25±0.10	0.50	0.40	0.60
FCB	1606	1.6±0.15	0.80±0.15	0.60±0.15	0.30±0.20	0.80	0.85	0.95
FCM	1608	1.6±0.15	0.80±0.15	0.80±0.15	0.30±0.20	0.80	0.85	0.95
HCB	0040	2.0±0.20	1.25±0.20	0.85±0.20	0.50±0.30	4.05	4.00	4.45
GHB	2012	2.0±0.20	1.25±0.20	1.25±0.20	0.50±0.30	1.05	1.00	1.45
FCI	<mark>3216</mark>	3.2±0.20	1.60±0.20	1.10±0.20	0.50±0.30	1.05	2.20	1.80
FHI	3225	3.2±0.20	2.50±0.20	1.30±0.20	0.50±0.30	1.05	2.20	2.70
FCH	4516	4.5±0.20	1.60±0.20	1.60±0.20	0.50±0.30	1.05	3.30	1.80
HCI	4532	4.5±0.20	3.20±0.20	1.50±0.20	0.50±0.30	1.05	3.30	3.40



Land
Solder Resist



PC board should be designed so that products can prevent damage from mechanical stress when warping the board.

6-2. Soldering

Mildly activated rosin fluxes are preferred. The terminations are suitable for re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

If wave soldering is used ,there will be some risk..

Re-flow soldering temperatures below 240 degrees, there will be unwitting risk

6-2.1 Lead Free Solder re-flow:

Recommended temperature profiles for lead free re-flow soldering in Figure 1. (Refered to J-STD-020C)

TAI-TECH KBM01-191000353 P6.

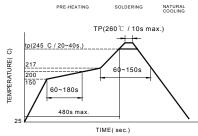
6-2.2 Soldering Iron:

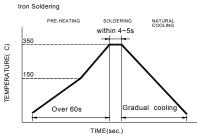
Products attachment with a soldering iron is discouraged due to the inherent process control limitations. If a soldering iron must be employed the following precautions are recommended. for Iron Soldering in Figure 2.

- Preheat circuit and products to 150℃
- · Never contact the ceramic with the iron tip
- Use a 20 watt soldering iron with tip diameter of 1.0mm
 Limit soldering time to 4~5sec.

- 350°C tip temperature (max)
- 1.0mm tip diameter (max)







Reflow times: 3 times max

6-2.3 Solder Volume: Fig.1

Accordingly increasing the solder volume, the mechanical stress to product is also increased. Exceeding solder volume may cause the failure of mechanical or electrical performance. Solder shall be used not to be exceed as shown in right side:

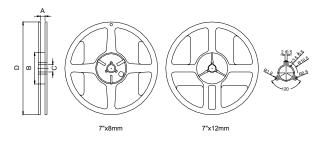
Minimum fillet height = soldering thickness + 25% product height

Iron Soldering times: 1 times max Fig.2



7. Packaging Information

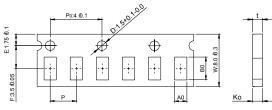
7-1. Reel Dimension



Туре	A(mm)	B(mm)	C(mm)	D(mm)
<mark>7"x8mm</mark>	9.0±0.5	<mark>60±2</mark>	<mark>13.5±0.5</mark>	178±2
7"x12mm	13.5±0.5	60±2	13.5±0.5	178±2

7-2.1 Tape Dimension / 8mm

■Material of taping is paper



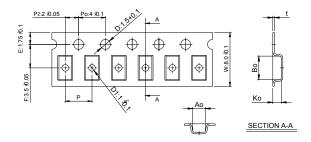
	P22.0.1 P04.0.1	<u>t</u> .
E:1.75 :0.1	8,39	
F:3.5 Ø.1		Ко

Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)
100505	1.12±0.03	0.62±0.03	0.60±0.03	2.0±0.05	0.60±0.03

Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)
160806	1.78±0.03	0.97±0.03	0.75±0.03	4.0±0.10	0.75±0.03
160808	1.80±0.05	0.96+0.05/-0.03	0.95±0.05	4.0±0.10	0.95±0.05
201209	2.10±0.05	1.30±0.05	0.95±0.05	4.0±0.10	0.95±0.05

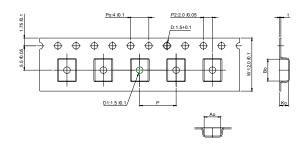
TAI-TECH KBM01-191000353 P7.

■Material of taping is plastic



Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)	D1(mm)
201212	2.10±0.10	1.28±0.10	1.28±0.10	4.0±0.10	0.22±0.05	1.0±0.10
<mark>321611</mark>	<mark>3.35±0.10</mark>	1.75±0.10	1.25±0.10	4.0±0.10	0.23±0.05	1.0±0.10
322513	3.42±0.10	2.77±0.10	1.55±0.10	4.0±0.10	0.22±0.05	1.0±0.10
321609	3.40±0.10	1.77±0.10	1.04±0.10	4.0±0.10	0.22±0.05	1.0±0.10

7-2.2 Tape Dimension / 12mm

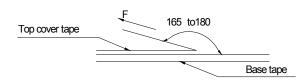


Size	Bo(mm)	Ao(mm)	Ko(mm)	P(mm)	t(mm)	D1(mm)
451616	4.70±0.10	1.75±0.10	1.75±0.10	4.0±0.10	0.24±0.05	1.5±0.10
453215	4.70±0.10	3.45±0.10	1.60±0.10	8.0±0.10	0.24±0.05	1.5±0.10

7-3. Packaging Quantity

Chip Size	453215	451616	322513	<mark>32161</mark>	1	321609	201212	201209	160808	160806	100505
Chip / Reel	1000	2000	2500	<mark>3000</mark>		3000	2000	4000	4000	4000	10000
Inner box	4000	8000	12500	<mark>15000</mark>		15000	10000	20000	20000	20000	50000
Middle box	20000	40000	62500	<mark>75000</mark>		75000	50000	100000	100000	100000	250000
Carton	40000	80000	125000	<mark>150000</mark>)	150000	100000	200000	200000	200000	500000

7-4. Tearing Off Force



The force for tearing off cover tape is 15 to 60 grams in the arrow direction under the following conditions.

Room Temp.	Room Humidity	Room atm	Tearing Speed
(°C)	(%)	(hPa)	mm/min
5~35	45~85	860~1060	300

Application Notice

- · Storage Conditions(component level)
 - To maintain the solderability of terminal electrodes:
 - 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.

 - 3. Recommended products should be used within 12 months from the time of delivery.
 - 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
 - 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
 - 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
 - 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.



Test Report

號碼(No.): CE/2018/C0389

日期(Date): 2018/12/11 頁數(Page): 1 of 15

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

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(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(中國,江蘇省,宿遷市,泗洪縣,經濟開發區杭州路南側,建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P. R., CHINA)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description)

: FERRITE CHIP BEAD > FERRITE CHIP INDUCTOR > ARRAY > MCF > MCM > YMV SERIES

樣品型號(Style/Item No.)

FERRITE CHIP BEAD · FERRITE CHIP INDUCTOR · ARRAY · MCF · MCM · YMV SERIES

收件日期(Sample Receiving Date)

2018/12/04

測試期間(Testing Period)

2018/12/04 to 2018/12/11

測試結果(Test Results) : 請參閱下一頁 (Please refer to following pages).



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Test Report

號碼(No.): CE/2018/C0389

日期(Date): 2018/12/11 頁數(Page): 2 of 15

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(慶邦電子元器件 (泗洪) 有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

林園市楊梅區幼獅工業區幼四路1號 / NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(中國,江蘇省,宿遷市,泗洪縣,經濟開發區杭州路南側,建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P, R, CHINA)

測試結果(Test Results)

測試部位(PART NAME)No.1

: 整體混測 (MIXED ALL PARTS)

测試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鍋 / Cadmium (Cd)	mg/kg	參考IEC 62321-5 (2013),以感應耦合 電漿原子發射光譜儀檢測. / With	2	n. d.
鉛 / Lead (Pb)	mg/kg	reference to IEC 62321-5 (2013) and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4 (2013),以感應耦合 電漿原子發射光譜儀檢測. / With reference to IEC 62321-4 (2013) and performed by ICP-AES.	2	n.d.
六價絡 / Hexavalent Chromium Cr(VI)	mg/kg	参考IEC 62321-7-2 (2017),以UV-VIS 檢測. / With reference to IEC 62321-7-2 (2017) and performed by UV-VIS.	8	n. d.
六溴環十二烷及所有主要被辨別出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α - HBCDD, β - HBCDD, γ - HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321 (2008),以氣相層析儀/ /質譜儀檢測. / With reference to IEC 62321 (2008). Analysis was performed by GC/MS.	5	n. d.

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西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(慶邦電子元器件 (泗洪) 有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

桃園市楊梅區幼獅工業區幼四路1號 / NO. 1, YOU 4TH ROAD, YOUTH INDUSTRIAL DISTRICT, YANG-MEI, TAO-YUAN CITY, TAIWAN, R. O. C.)

(江蘇省昆山市篷朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

(中國,江蘇省,宿遷市,泗洪縣,經濟開發區杭州路南側,建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST JIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P, R, CHINA)

測試項目 (Test Items)	單位 (Unit)	测試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result)
A should be a company of the company			(MDII)	No. 1
多溴聯苯總和 / Sum of PBBs	mg/kg	<u> </u>	-	n.d.
一溴聯苯 / Monobromobiphenyl	mg/kg]	5	n. d.
二溴聯苯 / Dibromobiphenyl	mg/kg	_	5	n. d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n. d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n. d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n. d
六溴聯苯 / Hexabromobiphenyl	mg/kg	1	5	n. d.
七溴聯苯 / Heptabromobiphenyl	mg/kg]	5	n. d.
へ溴聯苯 / Octabromobiphenyl	mg/kg]	5	n. d.
九溴聯苯 / Nonabromobiphenyl	mg/kg	】 参考IEC 62321-6 (2015),以氣相層析[5	n. d.
十溴聯苯 / Decabromobiphenyl	mg/kg	儀/質譜儀檢測. / With reference to	5	n. d
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	IEC 62321-6 (2015) and performed	_	n, d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg	by GC/MS.	5	n. d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg]	5	n. d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg]	5	n. d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg]	5	n. d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n. d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n. d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg] [5	n. d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg] [5	n. d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg] [5	n. d.
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg		5	n, đ.

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西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

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(慶邦電子元器件 (泗洪) 有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result)
				No. 1
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	mg/kg		50	n. d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	mg/kg		50	n. d.
鄰苯二甲酸二 (2-乙基己基)酯 / DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	mg/kg		50	n. d.
鄰苯二甲酸二異丁酯 / DIBP (Di- isobutyl phthalate) (CAS No.: 84-69- 5)	mg/kg	参考IEC 62321-8 (2017),以氣相層析	50	n. d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 26761- 40-0; 68515-49-1)	mg/kg	儀/質譜儀檢測. / With reference to IEC 62321-8 (2017). Analysis was performed by GC/MS.	50	n. d.
鄰苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 28553- 12-0; 68515-48-0)	mg/kg		50	n. d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n-octyl phthalate) (CAS No.: 117-84-0)	mg/kg		50	n. d.
鄰苯二甲酸二正己酯 / DNHP (Di-n-hexyl phthalate) (CAS No.: 84-75-3)	mg/kg		50	n. d.
鄰苯二甲酸二戊酯 / DNPP (Di-n-pentyl phthalate) (CAS No.: 131-18-0)	mg/kg		50	n. d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限値 (MDL)	結果 (Result) No.1
鹵素 / Halogen				
鹵素(氟)/ Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg		50	n. d.
鹵素(氯)/ Halogen-Chlorine (C1) (CAS No.: 22537-15-1)	mg/kg	参考BS EN 14582 (2016),以離子層析 儀分析. / With reference to BS EN	50	n. d.
鹵素(溴)/ Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg	14582 (2016). Analysis was performed by IC.	50	n. d.
鹵素(碘)/ Halogen-Iodine(I)(CAS No.: 14362-44-8)	mg/kg]	50	n. d.
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	參考US EPA 3550C (2007),以液相層 析儀/質譜儀檢測. / With reference to US EPA 3550C (2007). Analysis	10	n. d.
全氟辛酸 / PFOA (CAS No.: 335-67-1)	mg/kg	was performed by LC/MS.	10	n. d.
聚氯乙烯 / PVC	**	以紅外光譜分析及焰色法檢測. / Analysis was performed by FTIR and FLAME Test.	-	Negative
绨 / Antimony (Sb)	mg/kg	参考US EPA 3052 (1996),以感應耦合	2	n. d.
砷 / Arsenic (As)	mg/kg	電漿原子發射光譜儀檢測. / With reference to US EPA 3052 (1996).	2	n, d.
鈹 / Beryllium (Be)	mg/kg	Analysis was performed by ICP-AES.	2	n. d.

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備註(Note):

- 1. mg/kg = ppm : 0.1wt% = 1000ppm
- 2. n.d. = Not Detected (未檢出)
- 3. MDL = Method Detection Limit (方法偵測極限值)
- 4. "-" = Not Regulated (無規格值)
- 5. **= Qualitative analysis (No Unit) 定性分析(無單位)
- 6. Negative = Undetectable 陰性(未偵測到); Positive = Detectable 陽性(已偵測到)
- 7. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

PFOS濃度在物質或製備中不得超過0,001%(10ppm),在半成品、成品或零部件中不得超過0,1%(1000ppm),在紡織品或塗 層材料中不得超過lug/m²。

(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above lug/m^2 .)

8. 樣品的測試是基於申請人要求混合測試,報告中的混合測試結果不代表其中個別單一材質的含量. (The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

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Test Report

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

THE REPORT OF THE PROPERTY OF

(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

(慶邦電子元器件 (泗洪) 有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

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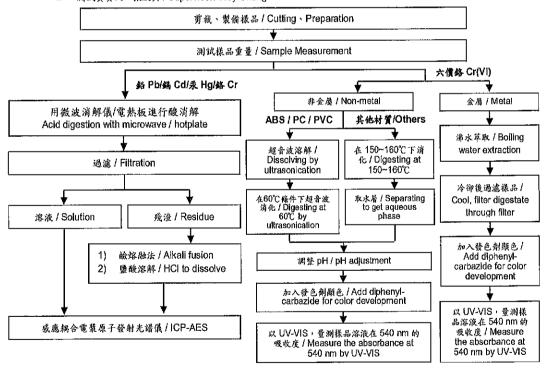
(中國,江蘇省,宿遷市,泗洪縣,經濟開發區杭州路南側,建設北路東側 / THE SOUTH HANGZHOU ROAD AND THE EAST IIANSHE ROAD, ECONOMIC DEVELOPMENT ZONE, SIHONG COUNTY, SUQIANCITY, JIANGSU PROVINCE, P. R., CHINA)

重金屬流程圖 / Analytical flow chart of Heavy Metal

根據以下的流程圖之條件,樣品已完全溶解。(六價鉻測試方法除外)

These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr8+ test method excluded)

- 测試人員:陳恩臻 / Technician: Rita Chen
- 測試負責人:張啟興 / Supervisor: Troy Chang



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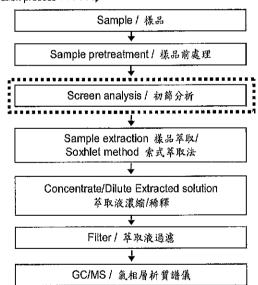
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多溴聯苯/多溴聯苯醚分析流程圖 / Analytical flow chart - PBB/PBDE

■ 測試人員:涂雅苓 / Technician: Yaling Tu

測試負責人:張啟興 / Supervisor: Troy Chang

初次测试程序 / First testing process ---確認程序 / Confirmation process - - - - →



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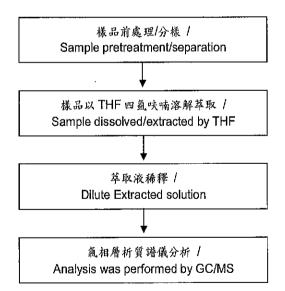
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可塑劑分析流程圖 / Analytical flow chart - Phthalate

測試人員:涂雅苓 / Technician: Yaling Tu

測試負責人:張啟興 / Supervisor: Troy Chang

【测試方法/Test method: IEC 62321-8】



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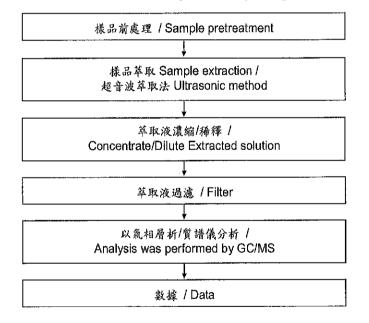
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六溴環十二烷分析流程圖 / Analytical flow chart - HBCDD

測試人員:涂雅苓 / Technician: Yaling Tu

測試負責人:張啟興 / Supervisor: Troy Chang



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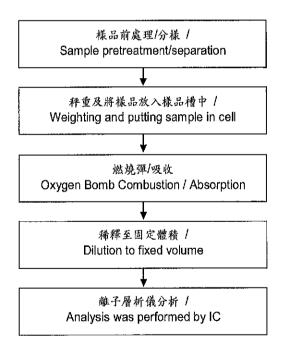
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鹵素分析流程圖 / Analytical flow chart - Halogen

測試人員:陳恩臻 / Technician: Rita Chen

測試負責人:張啟興 / Supervisor: Troy Chang



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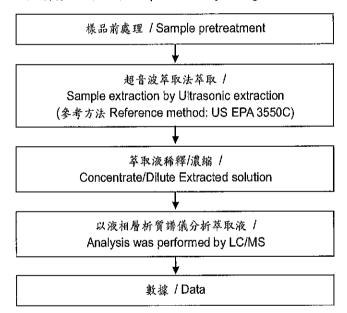
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全氟辛酸/全氟辛烷磺酸分析流程圖 / Analytical flow chart - PFOA/PFOS

- 測試人員:涂雅苓 / Technician: Yaling Tu
- 測試負責人:張啟興 / Supervisor: Troy Chang





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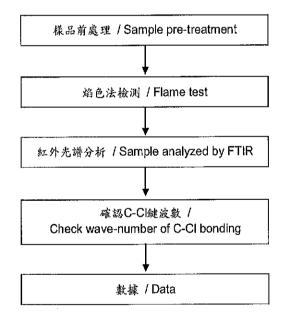
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聚氯乙烯物質判定分析流程圖 / Analysis flow chart - PVC

測試人員:涂雅苓 / Technician: Yaling Tu

測試負責人:張啟與 / Supervisor: Troy Chang





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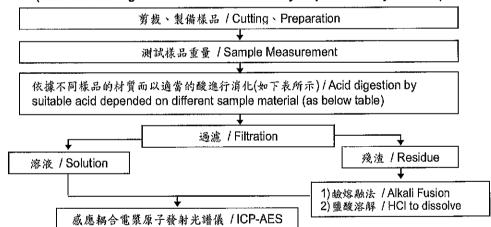
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> 根據以下的流程圖之條件,樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.

- 測試人員: 陳恩臻 / Technician: Rita Chen
- 測試負責人:張啟興 / Supervisor: Troy Chang

元素以 ICP-AES 分析的消化流程圖 (Flow Chart of digestion for the elements analysis performed by ICP-AES)



鲷,銅,鋁,焊錫 / Steel, copper, aluminum, solder	王水,硝酸,鹽酸,氫氟酸,雙氧水/
	Aqua regia, HNO ₃ , HCI, HF, H ₂ O ₂
玻璃 / Glass	硝酸,氫氟酸 / HNO3/HF
金,鉑,鲃,陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO ₃
塑膠 / Plastic	硫酸,雙氧水,硝酸,鹽酸 / H2SO4, H2O2, HNO3, HCI
其他 / Others	加入適當的試劑至完全溶解 / Added appropriate reagent to total digestion



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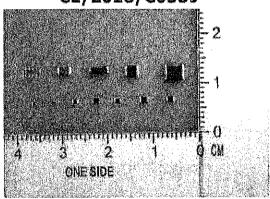
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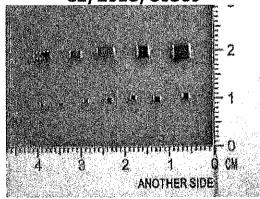
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> * 照片中如有箭頭標示,則表示為實際檢測之樣品/部位. * (The tested sample / part is marked by an arrow if it's shown on the photo.)

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